

IMEC239.001AUS



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

RECEIVED
FEB 24 2003
TECHNOLOGY CENTER 2800

Applicants : Vandervorst, et al.

App. No. : 10/091,226

Filed : February 28, 2002

For : METHOD AND APPARATUS
FOR PERFORMING ATOMIC
FORCE MICROSCOPY
MEASUREMENTS

Examiner : Unknown

I hereby certify that this correspondence and all marked
attachments are being deposited with the United States
Postal Service as first class mail in an envelope addressed
to: United States Patent and Trademark Office, P.O. Box
2327, Arlington, VA 22202, on

2/14/03
(Date)

John M. Carson, Reg. No. 34,503

PRELIMINARY AMENDMENT

United States Patent and Trademark Office
P.O. Box 2327
Arlington, VA 22202

Dear Sir:

Prior to examination of the above-identified application, please amend the application as follows:

IN THE SPECIFICATION:

Please insert the following paragraph between the title of the invention and background of the invention:

Related Applications

This application claims priority under 35 U.S.C. § 119(e) from U.S. Provisional Application No. 60/272,249, filed February 28, 2001, which is hereby incorporated by reference.